Application/Control No. Applicant(s)/Patent Under Reexamination 10/518,299 WATANABE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Van T. Trieu 2612 **U.S. PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Name Classification MM-YYYY US-7,088,249 08-2006 340/572.8 Senba et al. US-6,897,827 05-2005 Senba et al. 343/873 В US-6,160,526 343/895 С 12-2000 Hirai et al. US-D US-Ε US-F US-G US-Н US-1 US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY WO 02/07078 A1 01-2002 Japan Senba et al Ν * WO 02/07081 A1 01-2002 Japan Senba et al O Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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